

Notice of References Cited

Application/Control No.

10/581,322

Applicant(s)/Patent Under

Reexamination

FUKUI ET AL.

Examiner

SUN JAE Y. LOEWE

Art Unit

1626

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,470,807	12-2008	Shoda et al.	560/56
	B US-			
	C US-			
	D US-			
	E US-			
	F US-			
	G US-			
	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U Newman et al., DDT Vol 8, October 2003, pg. 898-90
	V Chawla et al., CRIPS Vol 5, No 1, January - March 2004, pg. 9-12
	W
	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.